TOSHIBA HIGH EFFICIENCY DIODE STACK (HED) SILICON EPITAXIAL TYPE

20DL2C41A, 20FL2C41A, 20GL2C41A

SWITCHING MODE POWER SUPPLY APPLICATION CONVERTER & CHOPPER APPLICATION

• Repetitive Peak Reverse Voltage : VRRM = 200 V, 300 V, 400 V

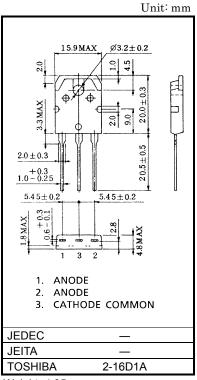
• Average Output Rectified Current : $I_O = 20 A$

Ultra Fast Reverse-Recovery Time : trr = 35 ns (Max)

• Low Switching Losses and Output Noise

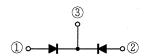
MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC		SYMBOL	RATING	UNIT	
Repetitive Peak Reverse Voltage	20DL2CZ41A		200	>	
	20FL2CZ41A	V_{RRM}	300		
	20GL2CZ41A		400		
Average Output Rectified Current		IO	20	Α	
Peak One Cycle Surge Forward		l=o	100 (50H _Z)	Α	
Current (Non Repeti	tive)	110 (60H _Z)			
Junction Temperature		Tj	-40~150	°C	
Storage Temperature Range		T _{stg}	-40~150	°C	
Screw Torque		_	0.8	N·m	

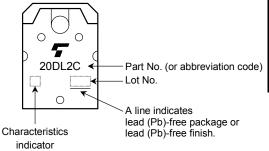


Weight: 4.85g

POLARITY



MARKING



Abbreviation Code	Part No.	
20DL2C	20DL2C41A	
20FL2C	20FL2C41A	
20GL2C	20GL2C41A	

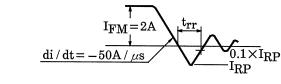


ELECTRICAL CHARACTERISTICS (Ta = 25°C)

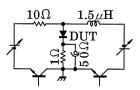
CHARACTERISTIC		SYMBOL	TEST CONDITION	TYP.	MAX	UNIT
Peak Forward Voltage (Note 1)	20DL2C41A		I _{FM} = 10A	_	0.98	V
	20FL2C41A	V_{FM}		_	1.3	
	20GL2C41A			_	1.8	
Repetitive Peak Reverse Current (Note 1)		I _{RRM}	V _{RRM} = Rated		50	μA
Reverse Recovery Time (Note 1)		t _{rr}	I _F = 2.0A, di / dt = - 50A / μs	_	35	ns
Forward Recovery Time (Note 1)		t _{fr}	I _F = 1A	_	100	ns
Thermal Resistance		R _{th (j−c)}	Total DC, Junction to Case	_	1.5	°C/W

Note 1: A value applied to one cell.

Note 2: trr Test Circuit

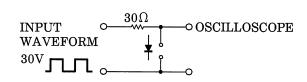


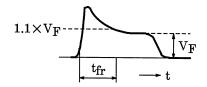
trr Waveform



Note 3: tfr Test Circuit

tfr Waveform





Handling Precaution

The maximum ratings denote the absolute maximum ratings, which are rated values and must not be exceeded during operation, even for an instant. The following are the general derating methods that we recommend when you design a circuit with a device.

VRRM: We recommend that the worst case voltage, including surge voltage, be no greater than 80% of the maximum rating of VRRM for a DC circuit and be no greater than 50% of that of VRRM for an AC circuit. VRRM has a temperature coefficient of 0.1%/°C. Take this temperature coefficient into account designing a device at low temperature.

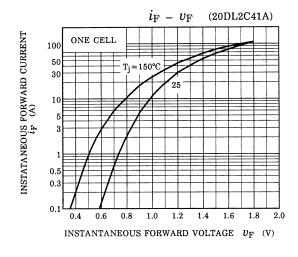
IO: We recommend that the worst case current be no greater than 80% of the maximum rating of IO. Carry out adequate heat design. If you can't design a circuit with excellent heat radiation, set the margin by using an allowable Tamax-IO curve.

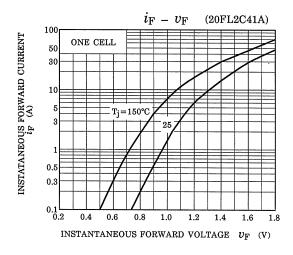
This rating specifies the non-repetitive peak current in one cycle of a 50-Hz sine wave, condition angle 180. Therefore, this is only applied for an abnormal operation, which seldom occurs during the lifespan of the device.

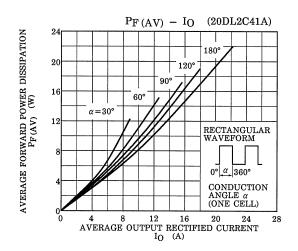
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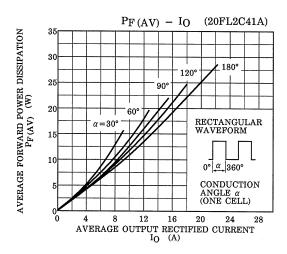
We recommend that a device be used at a Tj of below 120°C under the worst load and heat radiation conditions.

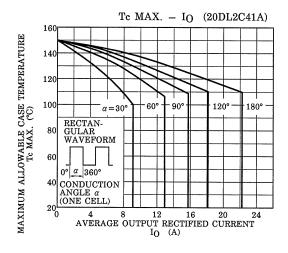
Please refer to the Rectifiers databook for further information.

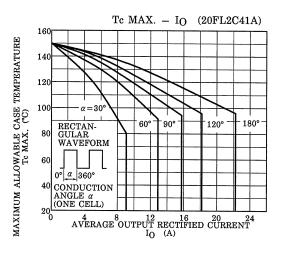


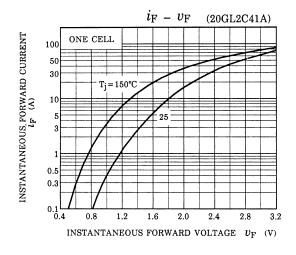


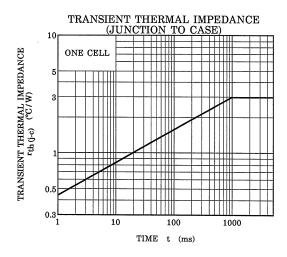


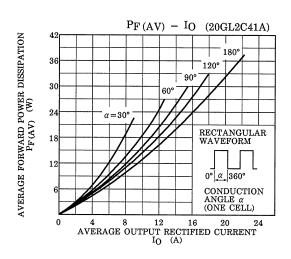


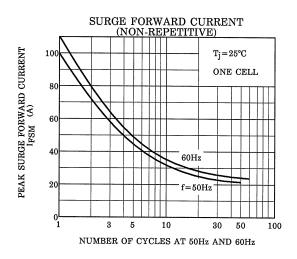


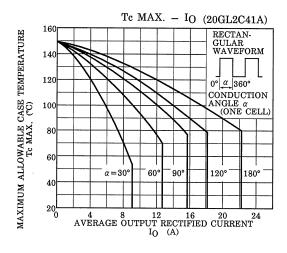


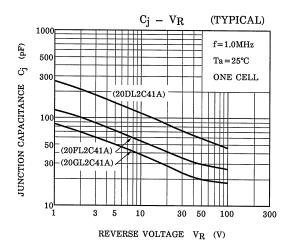












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